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Attorney Docket No. 0819-374

Serial No. Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Takeshi TAKAGI et al.

Filing Date: September , 2000

Group: Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,246,316	6/20/95	Mohammad			

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	Document Number	Date	Country	Class	Subclass	Translation Yes No
WS	6-66519	8/24/94	Japan			Abstract
	4-273491	9/29/92	Japan			Abstract
	6-204457	7/22/94	Japan			Abstract
	5-275717	10/22/93	Japan			Abstract
	5-259440	10/8/93	Japan			Abstract
	6-260493	9/16/94	Japan			Abstract
	2 288 691	10/25/95	United Kingdom			Full
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↓	09-283533	10/31/97	Japan			Abstract

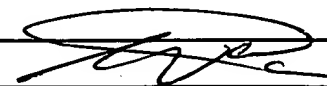
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Examiner

Date Considered

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0819-0374		Serial No. 09/659,484	
INFORMATION DISCLOSURE STATEMENT				Applicants: Takeshi TAKAGI et al.			
				Filing Date: September 11, 2000		Group Art Unit: 2814	
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	N
WSL	01-231371	09/14/1989	JP			Part. Eng. & Abst.	
	05-121677	05/18/1993	JP			Eng Abst	
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OTHER DOCUMENT (Including Author, Title, Date, Pertinent Pages, Etc.)							
Examiner Initial							
WSL	Notice of Reasons of Rejection, Patent Application No. 10-154689 Mailing Date: October 2, 2001, Mailing No. 2033500001, with English Translation						
WSL	Notice of Reasons of Rejection, Patent Application No. 10-154700 Mailing Date: October 2, 2001, Mailing No. 2033500007, with English Translation						
Examiner				Date Considered 9/30/02			
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Group Art Unit: 2814

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
WSV	803-198344	08/29/1991	JP			Part Eng	

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Examiner Initial	
WSV	Notice of Reasons of Rejection, Patent Application No. 10-154689 Mailing Date: June 4, 2002, Docket No. 2033500001, with Mailing No. 172502

Examiner

Date Considered

9/30/02

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